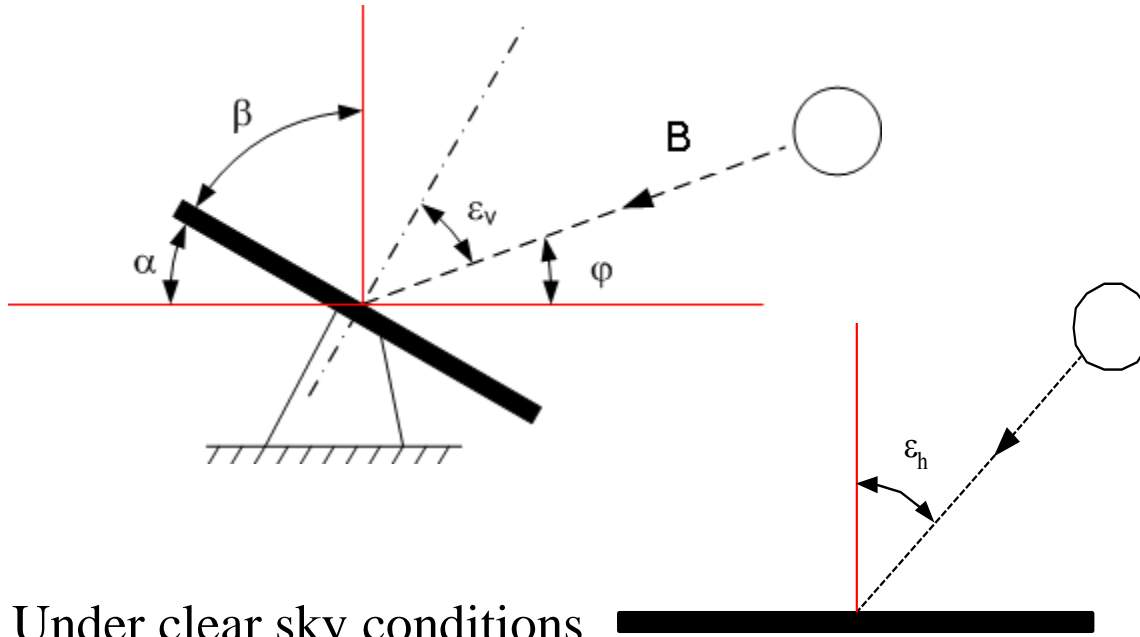


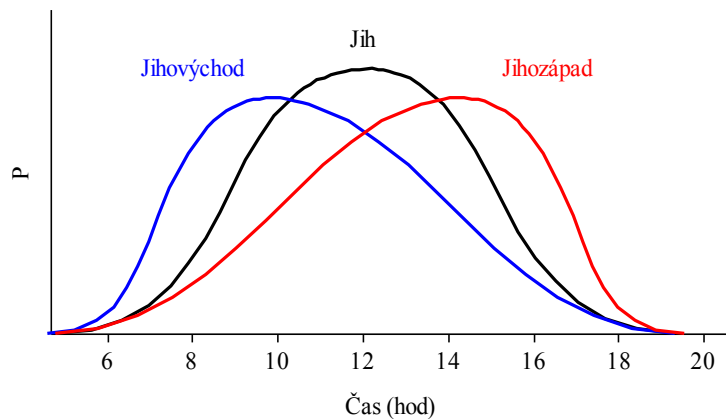
PV system operation conditions

A fixed construction (orientation, tilt angle)



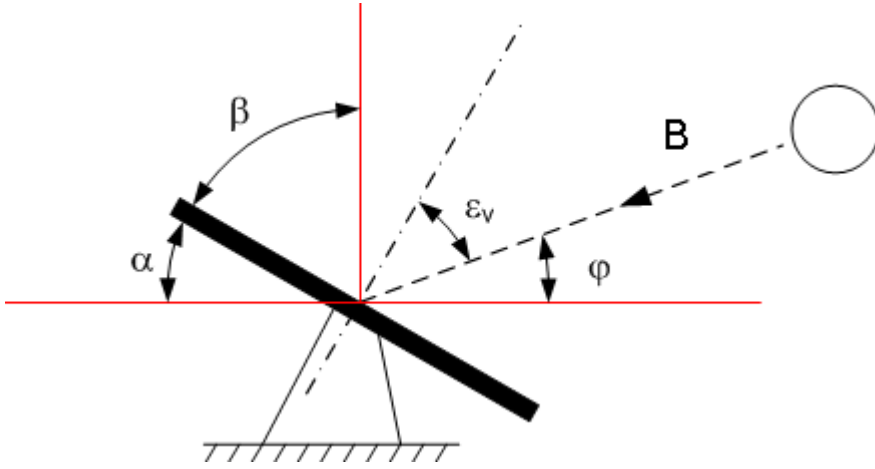
Under clear sky conditions

$$B(t) = 1367 \times 0.7 \frac{1}{\sin \varphi(t)} \cos \epsilon_v(t) \cos \epsilon_h(t)$$



Sun tracking systems

One axe tracking

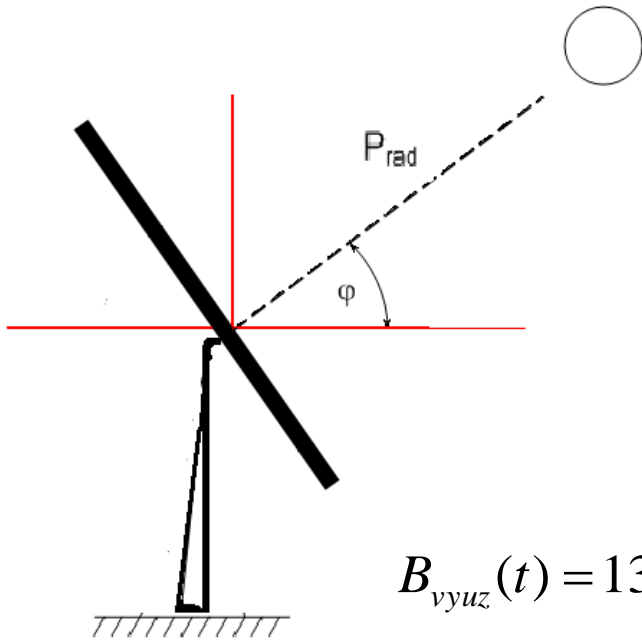


$$B_{vyuz}(t) = 1367 \times 0.7 \frac{1}{\sin \varphi(t)} \cos \varepsilon_v(t)$$

$$B_{vyuz}(t) = 1367 \times 0.7 \frac{1}{\sin \varphi(t)} \cos \varepsilon_h(t)$$

Sun tracking systems

Two axes tracking

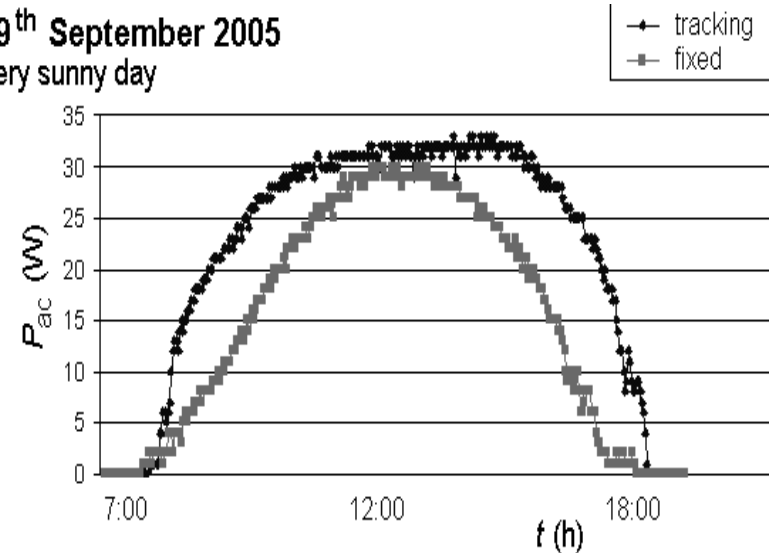


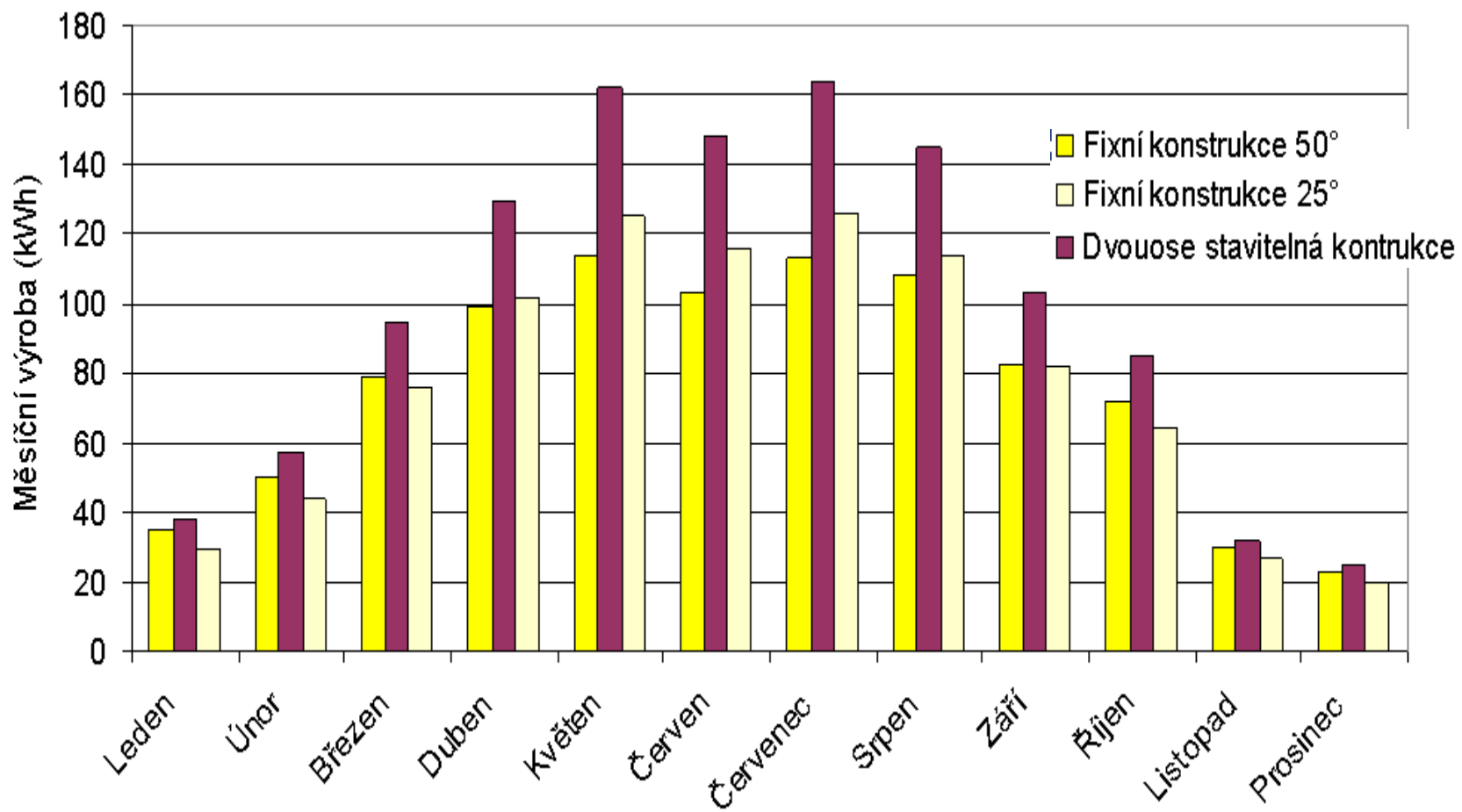
$$B_{vyuz}(t) = 1367 \times 0.7 \frac{1}{\sin \varphi(t)}$$

Systems with Sun tracking can produce of about 30% more energy than systems with a fixed construction



19th September 2005
very sunny day

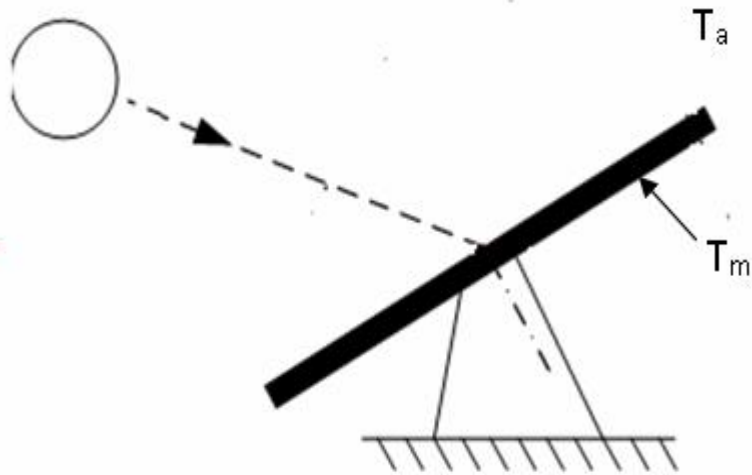




Influence of temperature

Open circuit voltage V_{OC} depends on the cell temperature T_c

$$V_{OC}(T_c) = V_{OC}^* + (T_c - T_c^*) \frac{dV_{OC}}{dT_c} \qquad T_c = T_m + \frac{G_{eff}}{G^*} \Delta T$$



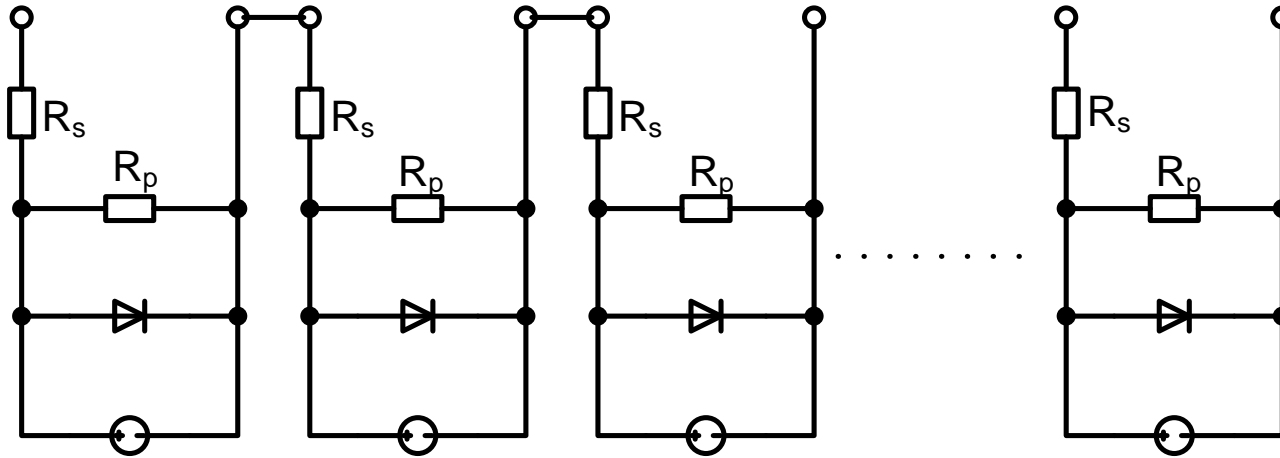
Temperature of the back surface T_m

$$T_m = T_a + \frac{G_{eff}}{G^*} [T_1 \exp(bv_w) + T_2]$$

v_w is the wind velocity

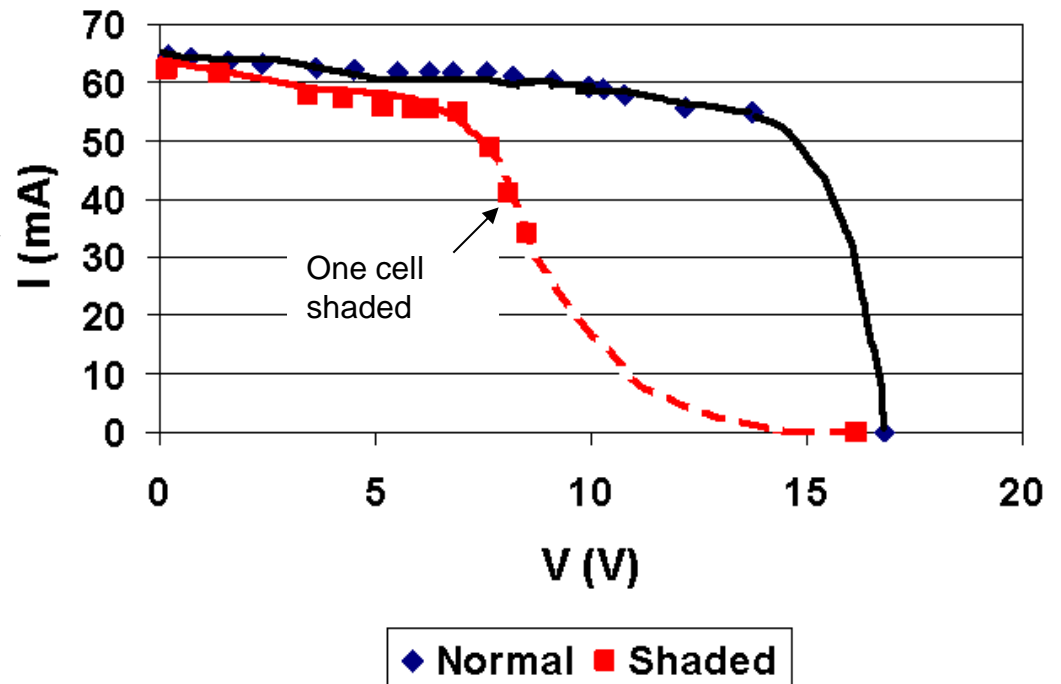
Type	T_1 [°C]	T_2 [°C]	b	ΔT [°C]
Glass/cell/glass	25.0	8.2	-0.112	2
Glass/cell/teflon	19.6	11.6	-0.223	3

Effect of partial shading – cells in series

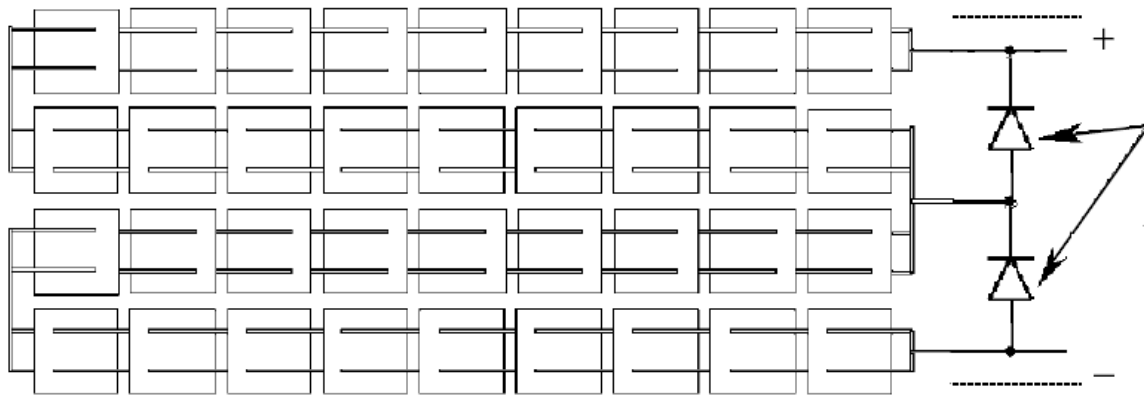


In the case of cells in series increases series resistance

- a decrease of the output current
- a decrease of the output voltage
- a considerable decrease of the output power

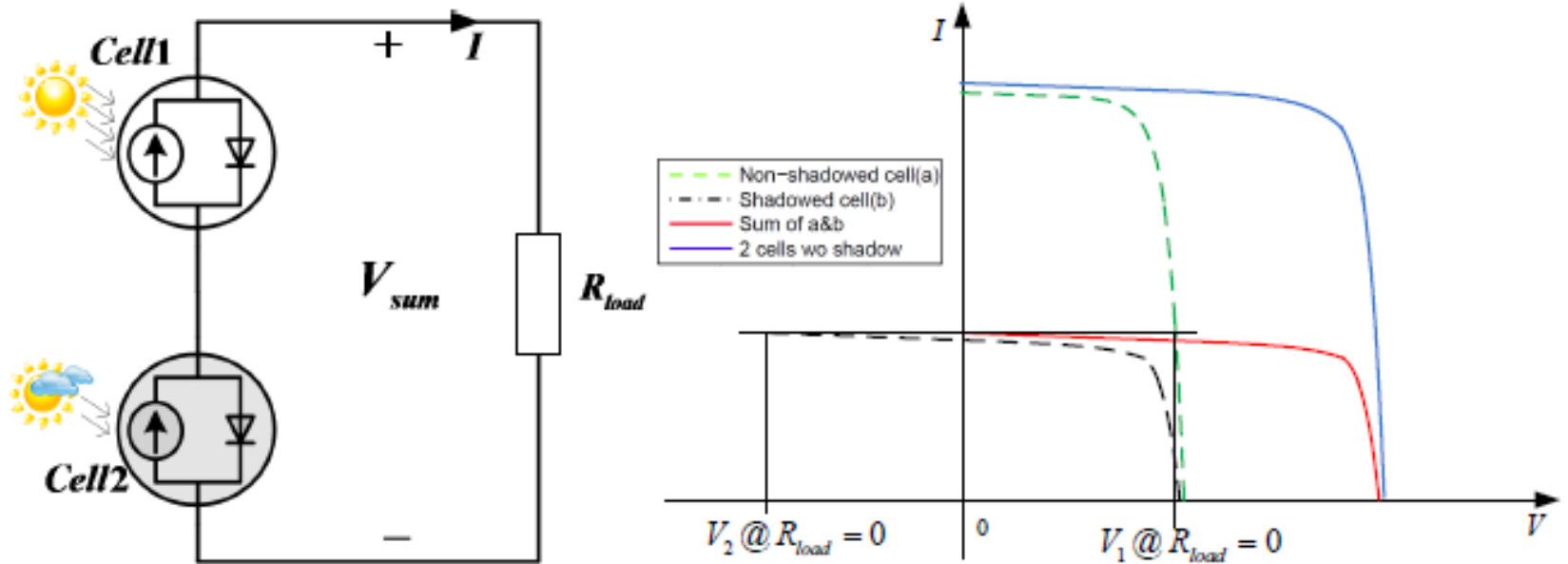


To eliminate possible hot spot origin, the approach followed is to put a diode (bypass diode) in parallel, but in opposite polarity, with a group cells



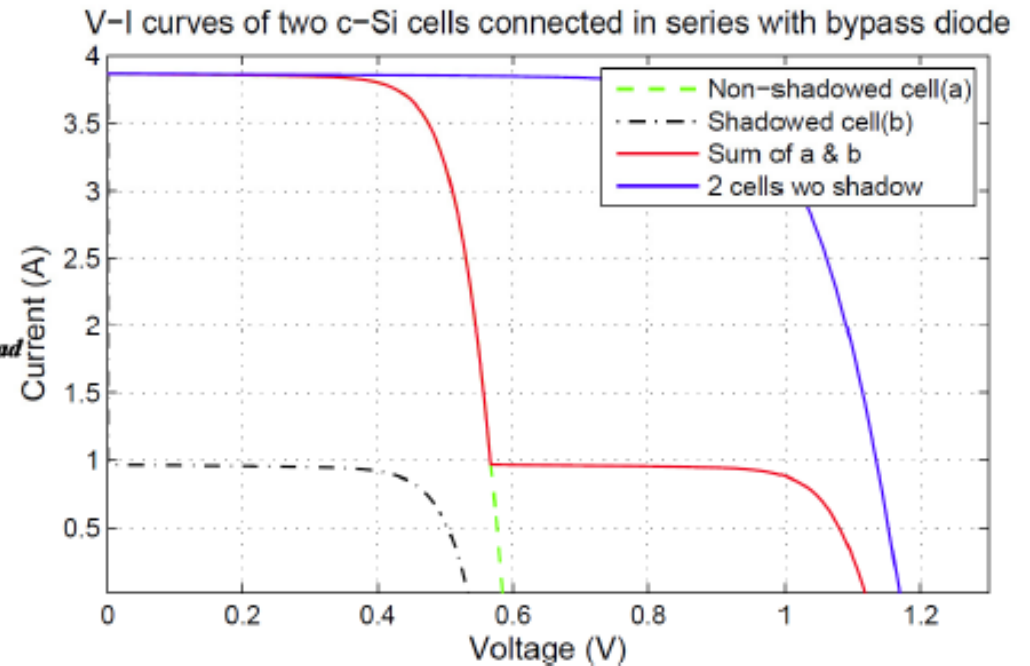
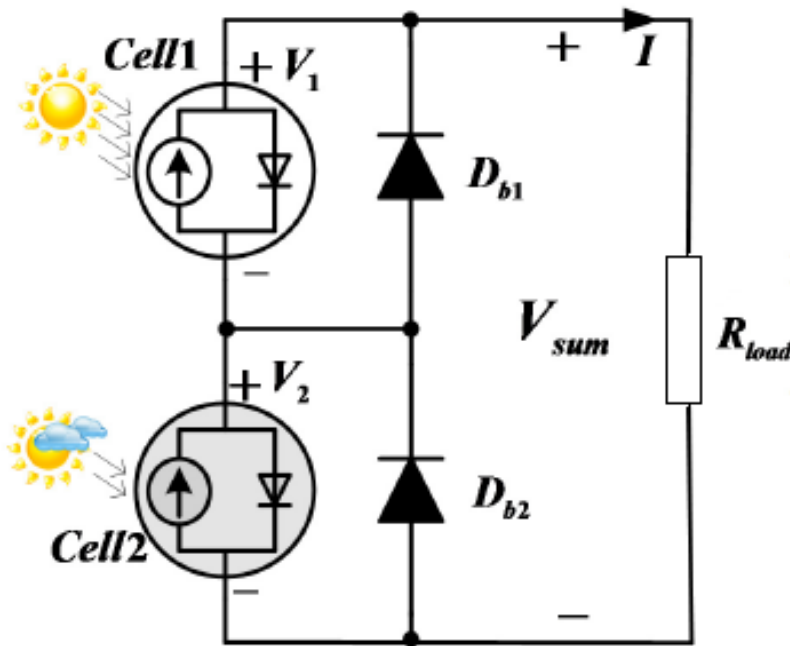
Bypass diodes are connected in the junction box 12 or 18 cells each

Non-uniform irradiation without bypass diodes



In case of no bypass diode, the cell with lower irradiance will limit the current

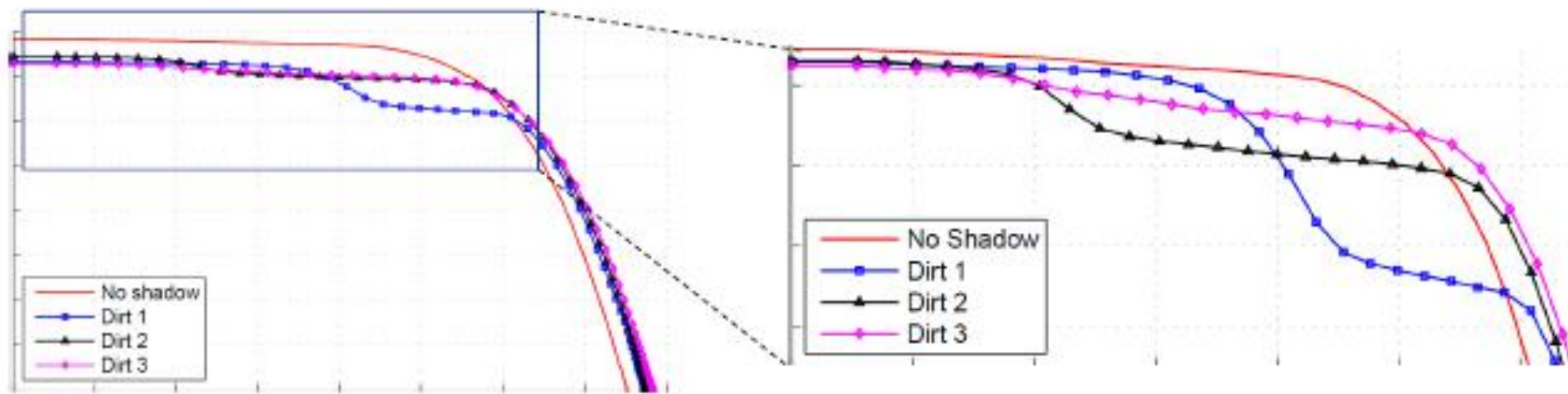
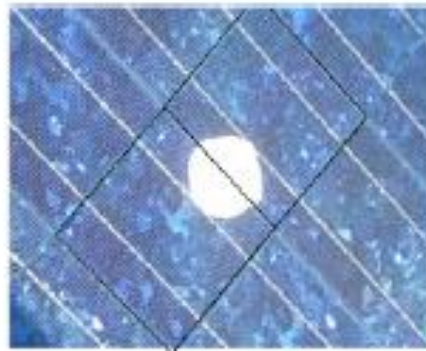
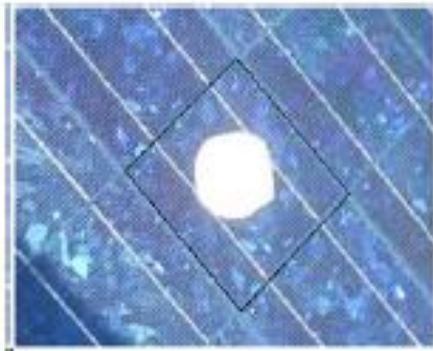
Non-uniform irradiation with bypass diodes



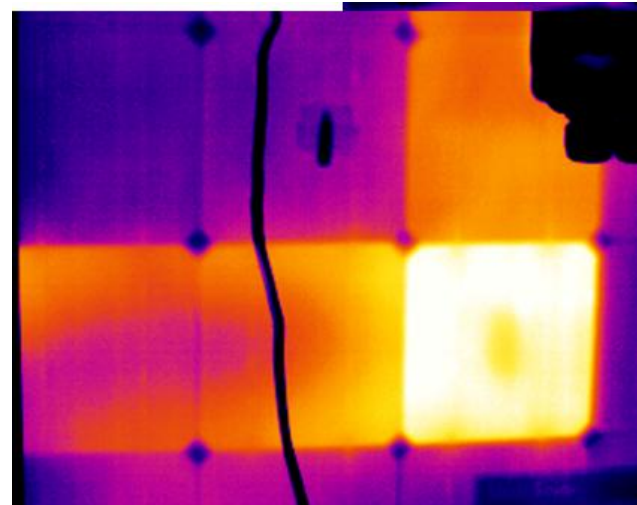
The bypass diode D_{b2} serves as path for the current, when I is larger than the short-circuit current of Cell 2

Soiling on PV modules

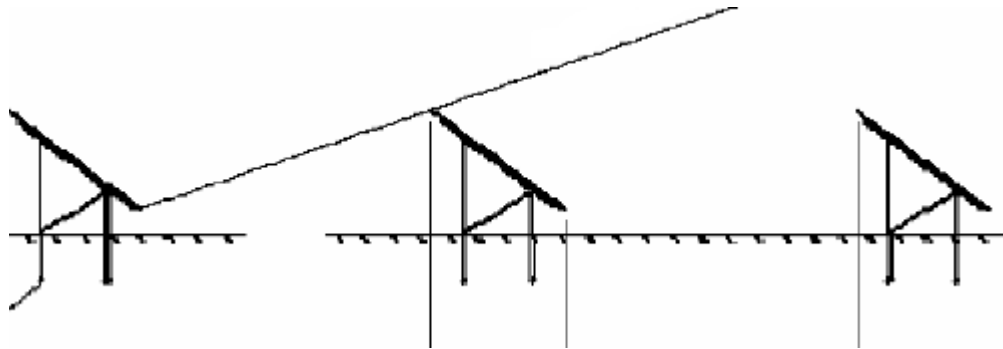
Even a small spot on a PV panel can significantly alter its characteristic



Temperature distribution on
partially shaded PV module



Distances between constructions should be projected with respect to possible shading



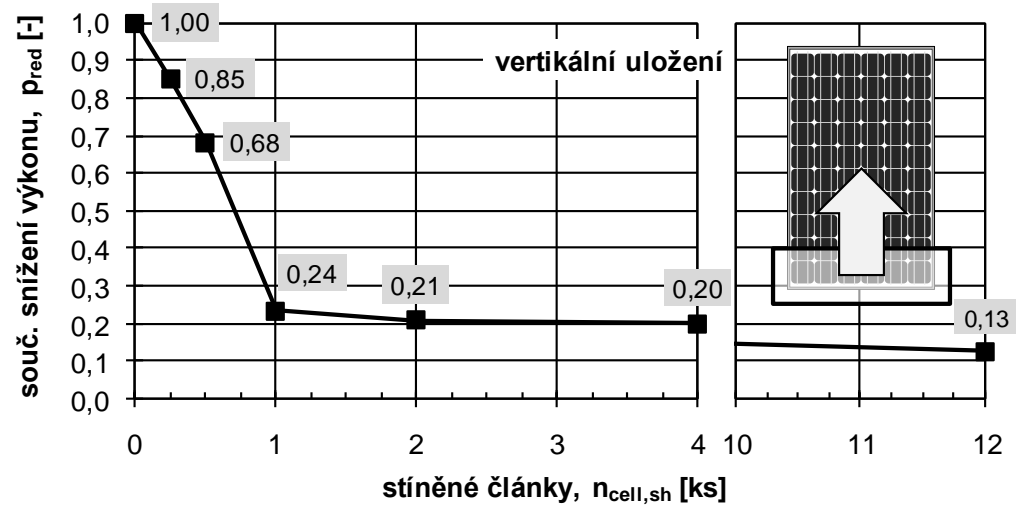
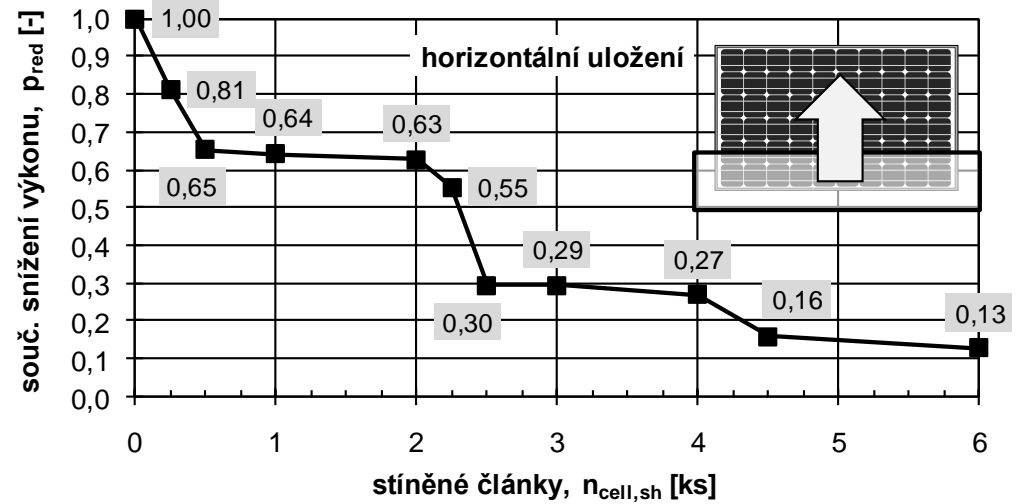
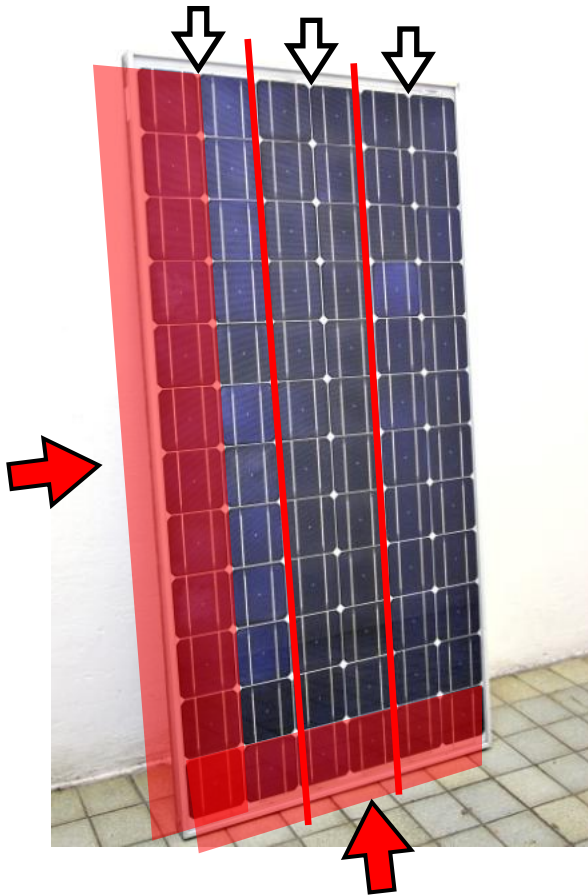
It is useful to take into account possible influence by objects in surrounding



The partial shading effect

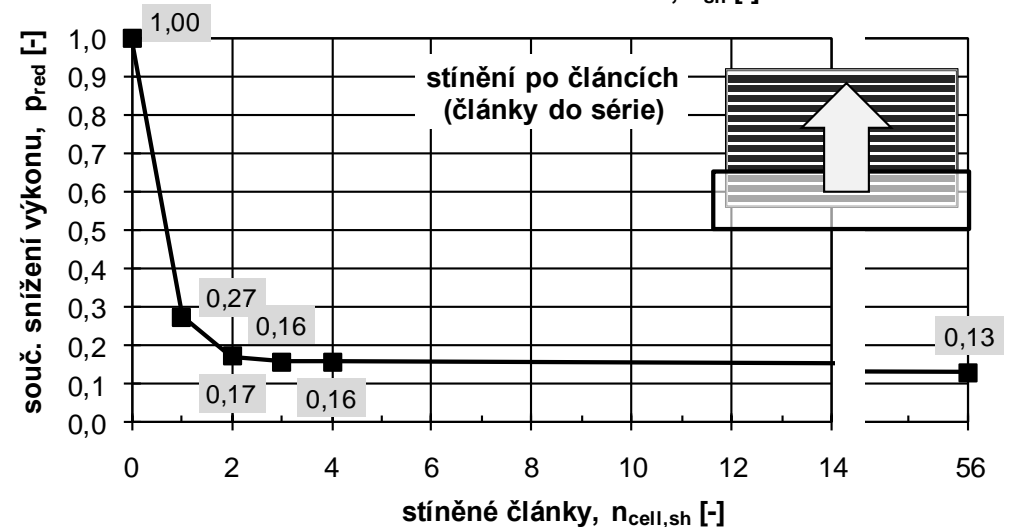
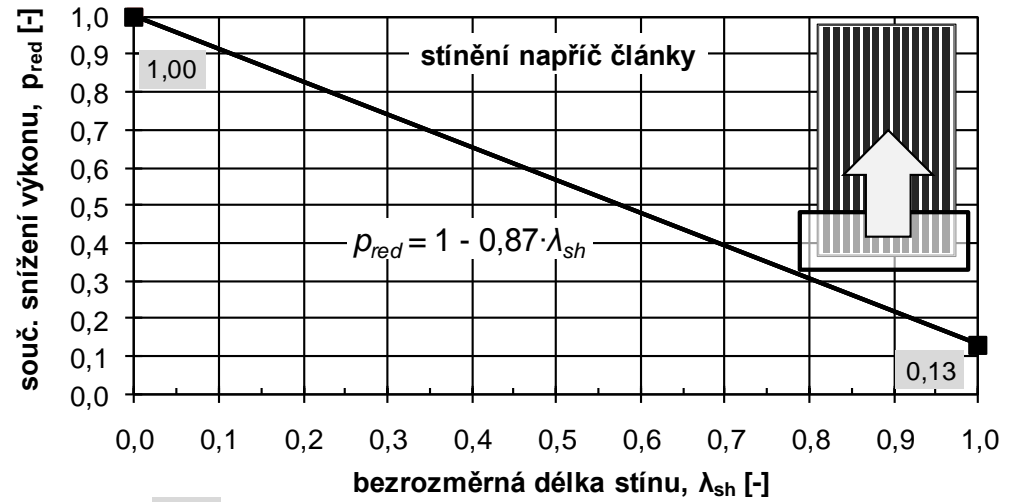
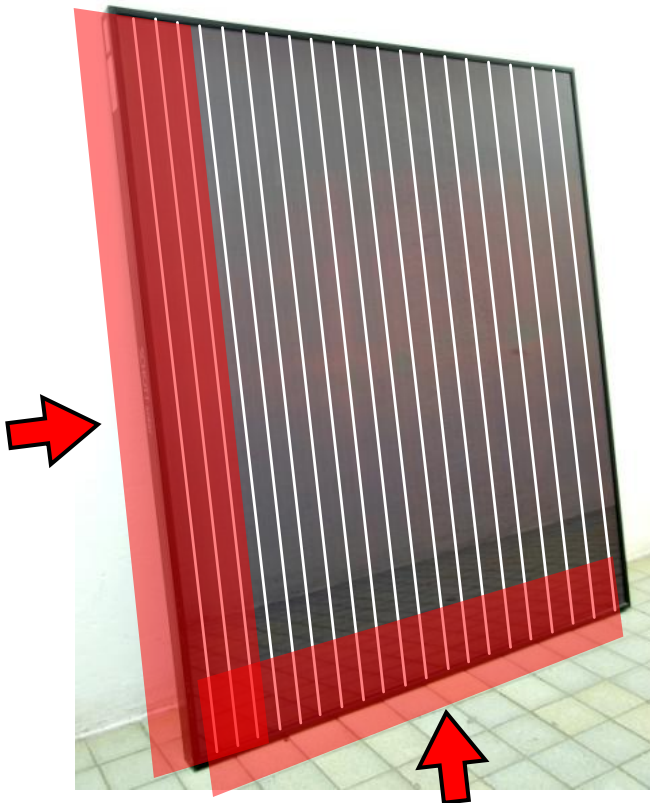
c-Si module:

➤ 3 bypass diods

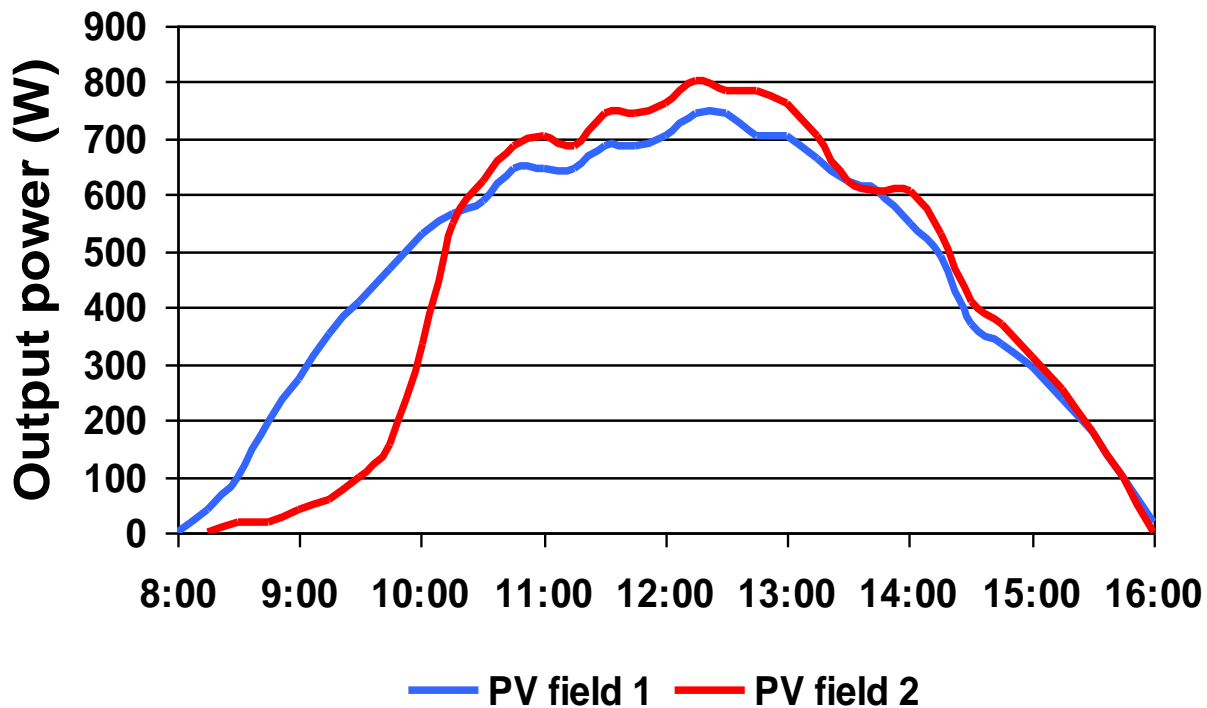
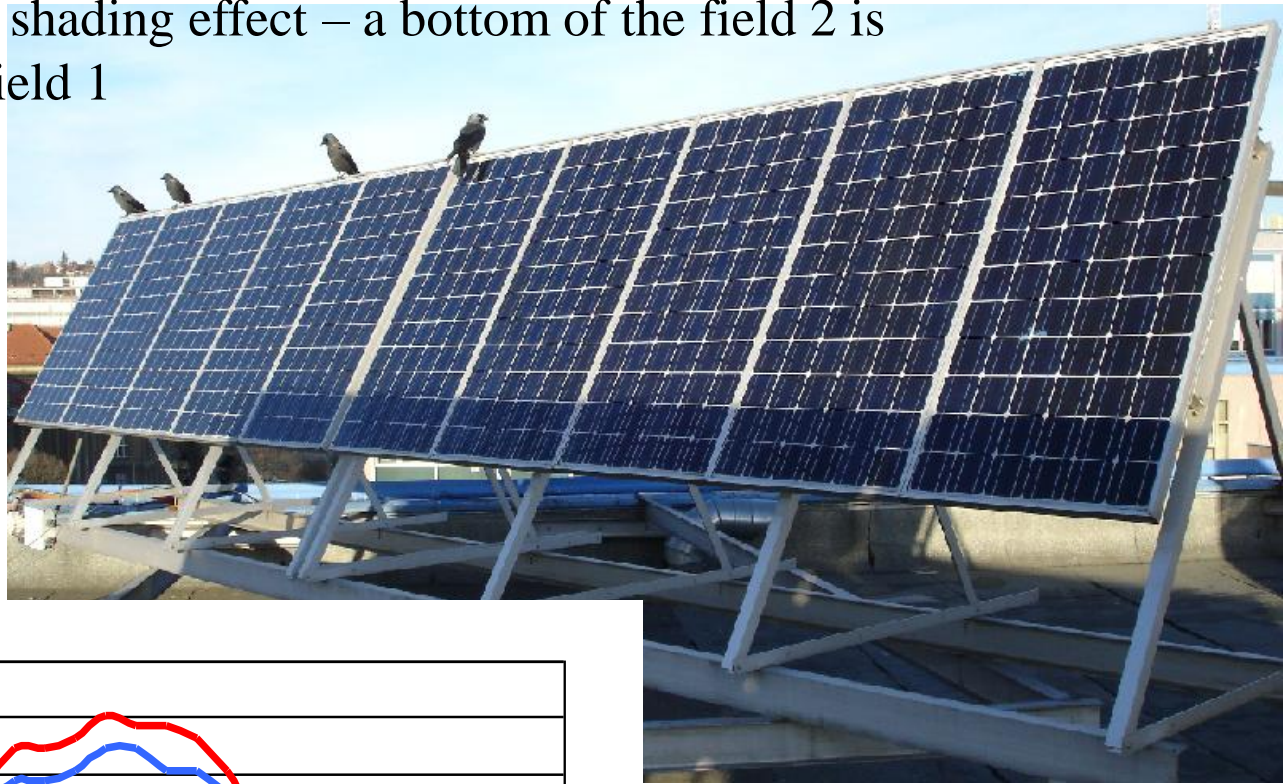


Thin film modules

➤ without diodes



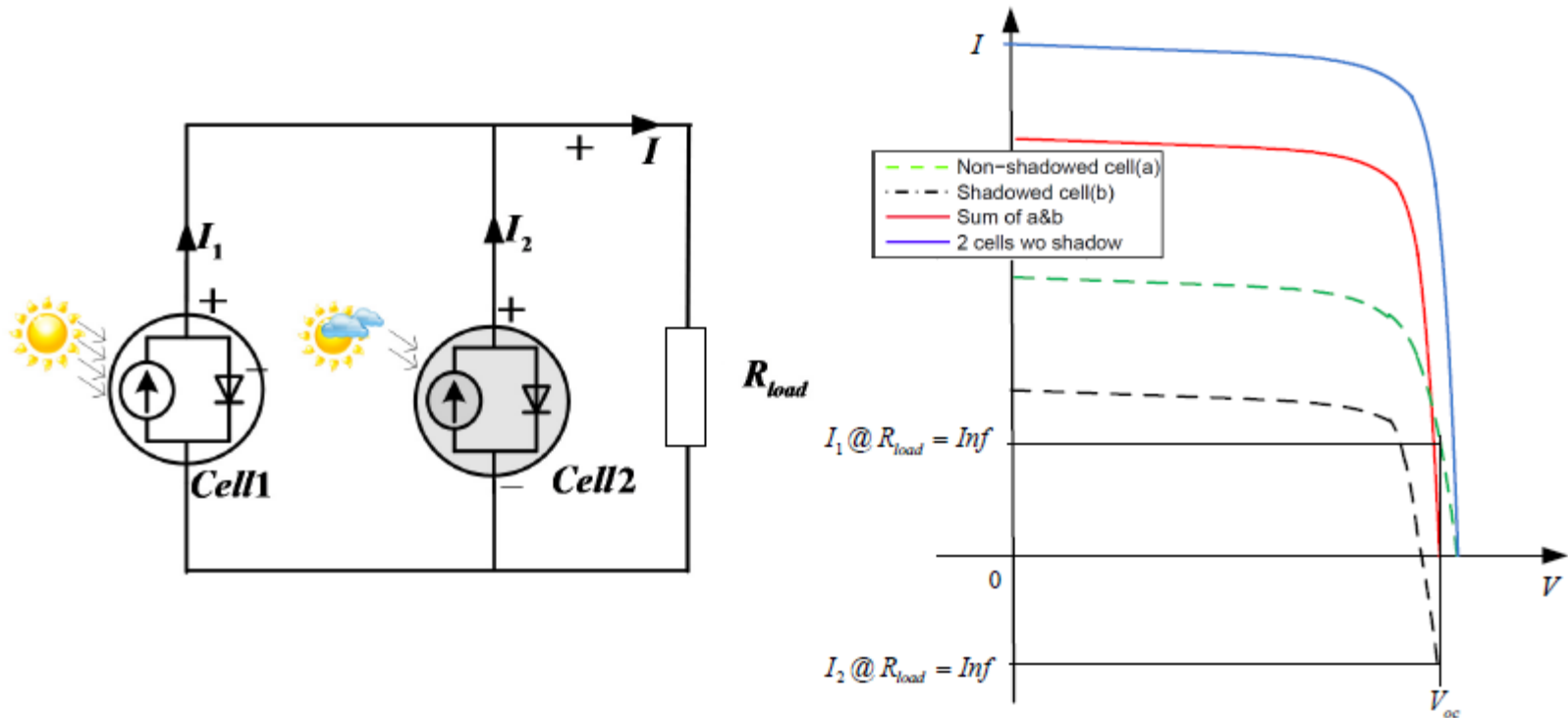
A practical example of the shading effect – a bottom of the field 2 is shaded in January by the field 1



Effect of snow



Non-uniform irradiation for parallel-connected cells



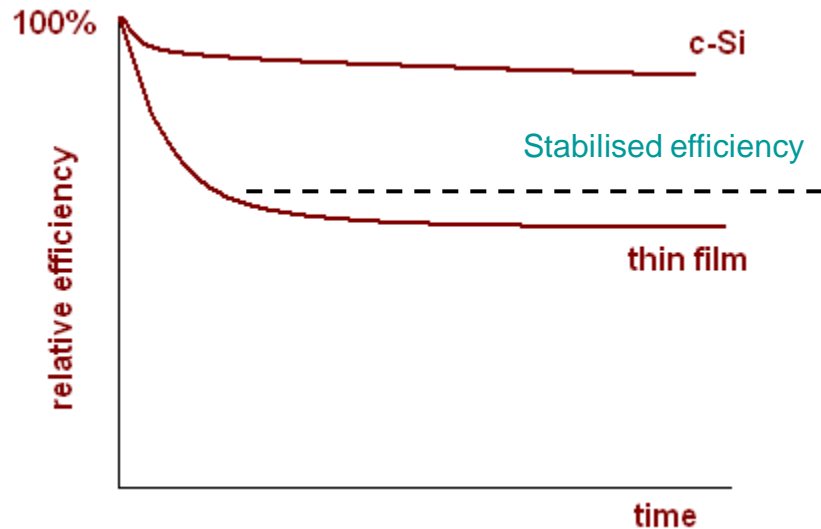
At open circuit and at light loads, the current can reverse in Cell 2

For parallel connected PV strings this is prevented by a blocking diode

Module lifetime

Time from starting electricity production till the output shall not fall below 80% of the rated value

Ageing – degradation processes



C-Si

Decrease of glass and EVA transparency, corrosion effects

Thin films

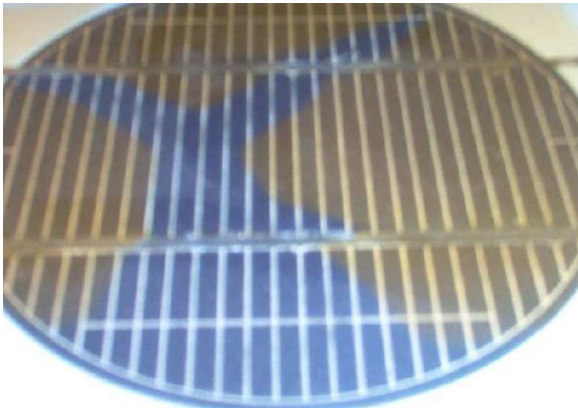
Thermo-mechanical stress
(adhesion and cohesion of interfaces)
Transparency of encapsulation, corrosion effects

Module type testing

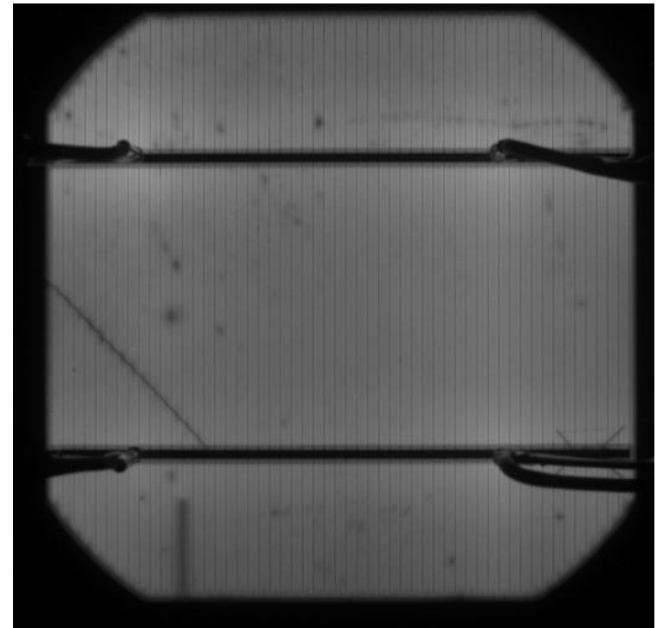
- Ultraviolet exposure using xenon lamps.
- Thermal cycling (-40°C to 50°C , 50 cycles) in conditioning chamber.
- Humidity freeze cycling (thermal cycling with 85% relative humidity).
- Damp heat (1000 h at 85°C and 90% relative humidity).
- Twist test for testing resistance to torques.
- Pressure is applied to the module to test resistance to static mechanical loads.
- Hail impact test, where the module is stricken by 25 mm diameter ice balls at 23 mseg^{-1} .
- Outdoor exposure.
- Hot spot tests, where the module is selectively shaded.

Reliability problems

- Environmental effect and aging results in a decrease of efficiency
 - a decrease of glass transparency
 - a decrease of EVA transparency (browning)
 - an increase of series resistance
 - degradation of individual layers of the cell structure



**A target: increase module
lifetime > 30 years**



Type of failure	Possible effect on the I-V curve
Corrosion[1,2]	Increased R_s → reduced FF
Cell interconnect break [2]	Increased R_s , reduced FF, PS
Decreased transparency of covering layers	
- Soiling	Reduced FF, PS
- Dust /Stain	Decreased peak power
- Discoloration of plastic encapsulates	Decreased peak power, reduced FF, PS
Mismatches	Reduced FF, PS
Ageing of the semiconductor material	Decreased peak power, reduced FF

FF – Fill Factor, PS – Partial Shadow

Series resistance increase is the main reason for module performance degradations

Electroluminescence

